

April 1988 Revised October 2000

74F543

Octal Registered Transceiver

General Description

The F543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow. The A outputs are guaranteed to sink 24 mA while the B outputs are rated for 64 mA.

Features

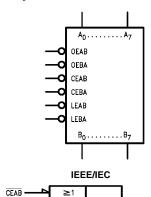
- 8-bit octal transceiver
- Back-to-back registers for storage
- Separate controls for data flow in each direction
- A outputs sink 24 mA
- B outputs sink 64 mA

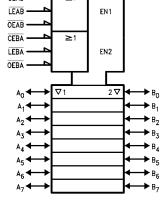
Ordering Code:

| Order Number | Package Number | Package Description |
|--------------|----------------|---|
| 74F543SC | M24B | 24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide |
| 74F543MSA | MSA24 | 24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide |
| 74F543PC | N24A | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-011, 0.600 Wide |
| 74F543SPC | N24C | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide |

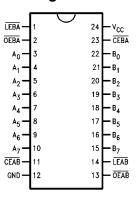
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols





Connection Diagram



Unit Loading/Fan Out

| Pin Names | Description | U.L. | Input I _{IH} /I _{IL} | |
|--------------------------------|---|----------------|---|--|
| Pin Names | Description | HIGH/LOW | Output I _{OH} /I _{OL} | |
| OEAB | A-to-B Output Enable Input (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | |
| OEBA | B-to-A Output Enable Input (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | |
| CEAB | A-to-B Enable Input (Active LOW) | 1.0/2.0 | 20 μA/–1.2 mA | |
| CEBA | B-to-A Enable Input (Active LOW) | 1.0/2.0 | 20 μA/–1.2 mA | |
| LEAB | A-to-B Latch Enable Input (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | |
| LEBA | B-to-A Latch Enable Input (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | |
| A ₀ -A ₇ | A-to-B Data Inputs or | 3.5/1.083 | 70 μΑ/–650 μΑ | |
| | B-to-A 3-STATE Outputs | 150/40 (33.8) | -3 mA/24 mA (20 mA) | |
| B ₀ -B ₇ | B-to-A Data Inputs or | 3.5/1.083 | 70 μΑ/–650 μΑ | |
| | A-to-B 3-STATE Outputs | 600/106.6 (80) | -12 mA/64 mA (48 mA) | |

Functional Description

The F543 contains two sets of eight D-type latches, with separate input and output controls for each set. For data flow from A to B, for example, the A-to-B Enable $(\overline{\text{CEAB}})$ input must be LOW in order to enter data from A_0-A_7 or take data from B_0-B_7 , as indicated in the Data I/O Control Table. With $\overline{\text{CEAB}}$ LOW, a LOW signal on the A-to-B Latch Enable ($\overline{\text{LEAB}}$) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the $\overline{\text{LEAB}}$ signal puts the A latches in the storage mode and their outputs no longer change with the A inputs. With $\overline{\text{CEAB}}$ and $\overline{\text{OEAB}}$ both LOW, the 3-STATE B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is similar, but using the $\overline{\text{CEBA}}$, $\overline{\text{LEBA}}$ and $\overline{\text{OEBA}}$ inputs.

Data I/O Control Table

| | Inputs | | Latch | Output | |
|------|--------|------|-------------|---------|--|
| CEAB | LEAB | OEAB | Status | Buffers | |
| Н | Х | Х | Latched | High Z | |
| Х | Н | Χ | Latched | _ | |
| L | L | Χ | Transparent | _ | |
| Х | Χ | Н | _ | High Z | |
| L | Х | L | _ | Driving | |

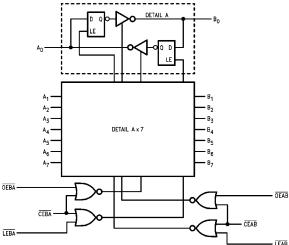
H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

A-to-B data flow shown; B-to-A flow control is the same, except using $\overline{\text{CEBA}}, \overline{\text{LEBA}}$ and $\overline{\text{OEBA}}$

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

 $-55^{\circ}C$ to $+150^{\circ}C$ Junction Temperature under Bias V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

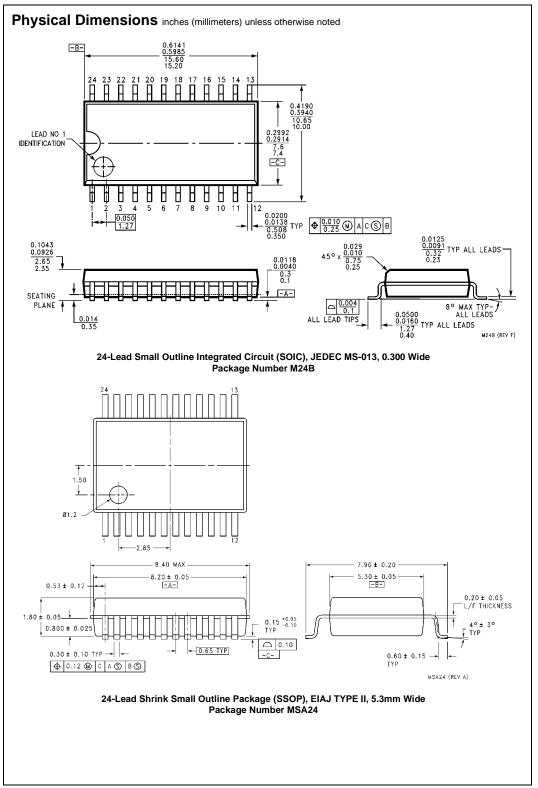
| Symbol | Parameter | | Min | Тур | Max | Units | V _{CC} | Conditions |
|------------------------------------|------------------------------|---------------------|------|------|------|--------|--|--|
| V _{IH} | Input HIGH Voltage | | 2.0 | | | V | | Recognized as a HIGH Signal |
| V _{IL} | Input LOW Voltage | | | | 0.8 | V | | Recognized as a LOW Signal |
| V _{CD} | Input Clamp Diode Voltage | | | | -1.2 | V | Min | I _{IN} = -18 mA |
| V _{OH} | Output HIGH Voltage | 10% V _{CC} | 2.5 | | | | | $I_{OH} = -1 \text{ mA } (A_n)$ |
| | | 10% V _{CC} | 2.4 | | | | | $I_{OH} = -3 \text{ mA } (A_n, B_n)$ |
| | | 5% V _{CC} | 2.7 | | | V | Min | $I_{OH} = -1 \text{ mA } (A_n)$ |
| | | 5% V _{CC} | 2.7 | | | | | $I_{OH} = -3 \text{ mA } (A_n, B_n)$ |
| | | 10% V _{CC} | 2.0 | | | | | $I_{OH} = -15 \text{ mA } (B_n)$ |
| V _{OL} | Output LOW | 10% V _{CC} | | | 0.5 | V | Min | $I_{OL} = 24 \text{ mA } (A_n)$ |
| | Voltage | 10% V _{CC} | | | 0.55 | | | $I_{OL} = 64 \text{ mA } (B_n)$ |
| I _{IH} | Input HIGH Current | | | | 5.0 | μΑ | Max | $V_{IN} = 2.7V$ |
| I _{BVI} | Input HIGH Current | | | | 7.0 | | | (OEAB, OEBA, LEAB, |
| | Breakdown Test | | | | 7.0 | μΑ | Max | LEBA, CEAB, CEBA) |
| I _{BVIT} | Input HIGH Current | | | | 0.5 | mA | Max | V 55V (A B) |
| | Breakdown (I/O) | | | | 0.5 | mA | IVIAX | $V_{IN} = 5.5V (A_n, B_n)$ |
| I _{CEX} | Output HIGH | | | | 50 | | Max | V V |
| | Leakage Current | | | | 50 | μА | IVIAX | $V_{OUT} = V_{CC}$ |
| V _{ID} | Input Leakage | | 4.75 | | | V | 0.0 | I _{ID} = 1.9 μA |
| | Test | | 4.75 | | | • | 0.0 | All Other Pins Grounded |
| I _{OD} | Output Leakage | | | | 3.75 | μА | μA 0.0 | $V_{IOD} = 150 \text{ mV}$ |
| | Circuit Current | | | | 0.70 | μιτ | 0.0 | All Other Pins Grounded |
| I _{IL} | Input LOW Current | | | | -0.6 | mA | | $V_{IN} = 0.5V (\overline{OEAB}, \overline{OEBA})$ |
| | | | | -1.2 | Max | | $V_{IN} = 0.5V (\overline{CEAB}, \overline{CEBA})$ | |
| I _{IH} + I _{OZH} | Output Leakage Curren | t | | | 70 | μΑ | Max | $V_{OUT} = 2.7V (A_n, B_n)$ |
| I _{IL} + I _{OZL} | Output Leakage Curren | t | | | -650 | μΑ | Max | $V_{OUT} = 0.5V (A_n, B_n)$ |
| Ios | Output Short-Circuit Current | | -60 | | -150 | mA Max | May | $V_{OUT} = 0V (A_n)$ |
| | | | -100 | | -225 | | IVIAX | $V_{OUT} = 0V (B_n)$ |
| I _{ZZ} | Bus Drainage Test | | | | 500 | μА | 0.0V | $V_{OUT} = 5.25V (A_n, B_n)$ |
| I _{CCH} | Power Supply Current | | | 67 | 100 | mA | Max | V _O = HIGH |
| I _{CCL} | Power Supply Current | | | 83 | 125 | mA | Max | $V_O = LOW$ |
| I _{CCZ} | Power Supply Current | | | 83 | 125 | mA | Max | V _O = HIGH Z |

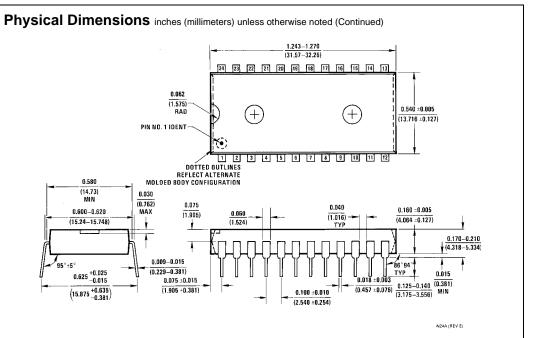
AC Electrical Characteristics

| Symbol | Parameter | | $T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$ | | $T_A = 0$ °C to +70°C $C_L = 50 \text{ pF}$ | | Units |
|------------------|--|-----|---|------|---|------|-------|
| | | Min | Тур | Max | Min | Max | |
| t _{PLH} | Propagation Delay | 3.0 | 5.5 | 7.5 | 3.0 | 8.5 | |
| t _{PHL} | Transparent Mode | 3.0 | 5.0 | 6.5 | 3.0 | 7.5 | ns |
| | A_n to B_n or B_n to A_n | | | | | | |
| t _{PLH} | Propagation Delay | 4.5 | 8.5 | 11.0 | 4.5 | 12.5 | ns |
| t _{PHL} | LEBA to A _n | 4.5 | 8.5 | 11.0 | 4.5 | 12.5 | 115 |
| t _{PLH} | Propagation Delay | 4.5 | 8.5 | 11.0 | 4.5 | 12.5 | ns |
| t _{PHL} | LEAB to B _n | 4.5 | 8.5 | 11.0 | 4.5 | 12.5 | 115 |
| t _{PZH} | Output Enable Time | | | | | | |
| t_{PZL} | OEBA or OEAB to A _n or B _n | 3.0 | 7.0 | 9.0 | 3.0 | 10.0 | |
| | CEBA or CEAB to A _n or B _n | 4.0 | 7.5 | 10.5 | 4.0 | 12.0 | ns |
| t _{PHZ} | Output Disable Time | | | | | | 115 |
| t _{PLZ} | OEBA or OEAB to A _n or B _n | 1.0 | 6.0 | 8.0 | 1.0 | 9.0 | |
| | CEBA or CEAB to A _n or B _n | 2.5 | 5.5 | 10.5 | 2.5 | 11.5 | |

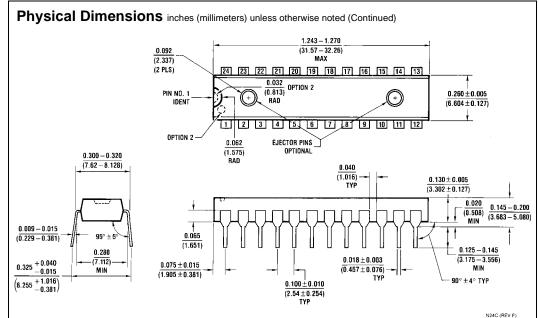
AC Operating Requirements

| Symbol | Parameter | | +25°C - +5.0V | T _A = 0°C | Units | |
|--------------------|--|-----|------------------|----------------------|-------|-----|
| | | Min | Max | Min | Max | 1 |
| t _S (H) | Setup Time, HIGH or LOW | 3.0 | | 3.5 | | |
| t _S (L) | A _n or B _n to LEBA or LEAB | 3.0 | | 3.5 | | ns |
| t _H (H) | Hold Time, HIGH or LOW | 3.0 | | 3.5 | | 115 |
| t _H (L) | A _n or B _n to LEBA or LEAB | 3.0 | | 3.5 | | |
| t _W (L) | Latch Enable, B to A or | 8.0 | | 9.0 | | ne |
| | B to A Pulse Width, LOW | 6.0 | | 9.0 | | ns |





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-011, 0.600 Wide Package Number N24A



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N24C

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